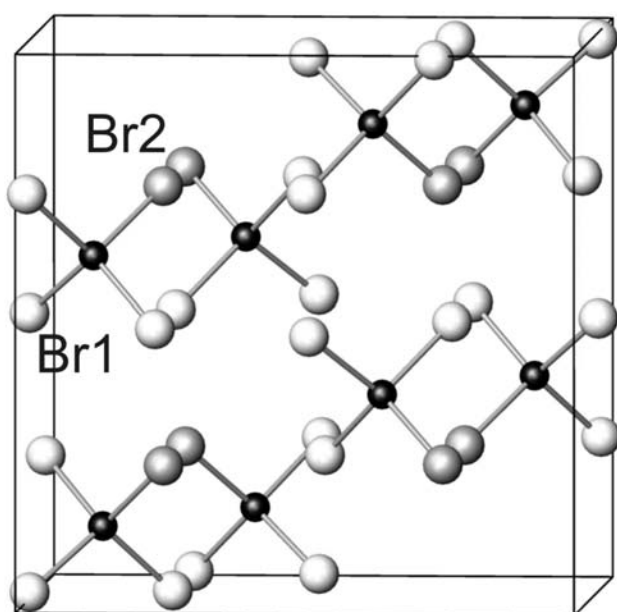


Refinement of the crystal structure of α -silicon tetrabromide, α -SiBr₄, a room temperature modification

Jianwei Tong, Constantin Hoch, Arndt Simon and Jürgen Köhler*

Max-Planck-Institut für Festkörperforschung, Heisenbergstraße 1, 70569 Stuttgart, Germany

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Abstract

Br₄Si, *Pa* $\bar{3}$ (no. 205), *a* = 11.152(1) Å, *V* = 1386.9 Å³, *Z* = 8, *R*_{gt}(*F*) = 0.046, *wR*_{ref}(*F*²) = 0.087, *T* = 223 K.

Source of material

Liquid SiBr₄ (Aldrich, 99.995 %) was filled in capillaries with 0.3 mm diameter under argon. In the capillary colorless transparent single crystals of SiBr₄ were grown by rapidly freezing one end of the liquid and solidifying the remaining part slowly at 223 K on a STOE IPDS I diffractometer with a temperature control equipment.

Discussion

SiBr₄ (m.p. 278 K) is known since more than 100 years [1,2]. Recently, the crystal structures of two out of ten possible structure types for SiBr₄ predicted by global minimization of the lattice energy using the program CRYSCA were found [3]. Temperature dependent X-ray powder diffraction studies show that at a transition temperature of 168 K the monoclinic low-temperature β -phase transforms into the high-temperature cubic α -phase. The cubic α -SiBr₄ is isotypic to α -GeBr₄ [4] and adopts the SnI₄ type structure [3]. Monoclinic β -SiBr₄ [5] crystallizes like β -GeBr₄ [6] in the SnBr₄ type structure. The structure of the high temperature modification, α -SiBr₄, has been refined using single crystal X-ray diffraction data taken at 223 K. It can be described in terms of a cubic close packing of Br atoms in which one eighth of the tetrahedral holes are occupied by Si atoms. In α -SiBr₄ each Si atom is surrounded by one Br1 and three Br2 atoms to form a tetrahedron with Si—Br1 distances of 2.193(5) Å and Si—Br2 distances of 2.189(4) Å (3×), respectively. The Br—Si—Br angles are 109.6(1)° and 109.3(1)°, close to the angle in an ideal tetrahedron. Each Br atom is cuboctahedrally surrounded by other Br atoms. The three Br—Br distances belonging to a SiBr₄ tetrahedron lie between 3.57 and 3.58 Å, whereas the remaining nine Br—Br distances are longer (3.94 to 4.23 Å).

Table 1. Data collection and handling.

Crystal:	colorless cube, size 0.3 × 0.3 × 0.3 mm
Wavelength:	Mo <i>K</i> α radiation (0.71073 Å)
μ :	232.52 cm ^{−1}
Diffractometer, scan mode:	STOE IPDS II, ω
$2\theta_{\max}$:	39.96°
<i>N</i> (<i>hkl</i>) _{measured} , <i>N</i> (<i>hkl</i>) _{unique} :	4180, 215
Criterion for <i>I</i> _{obs} , <i>N</i> (<i>hkl</i>) _{gt} :	<i>I</i> _{obs} > 2 σ (<i>I</i> _{obs}), 188
<i>N</i> (<i>param</i>) _{refined} :	17
Programs:	SHELXS-97, SHELXL-97 [7]

Table 2. Atomic coordinates and displacement parameters (in Å²).

Atom	Site	<i>x</i>	<i>y</i>	<i>z</i>	<i>U</i> ₁₁	<i>U</i> ₂₂	<i>U</i> ₃₃	<i>U</i> ₁₂	<i>U</i> ₁₃	<i>U</i> ₂₃
Br(1)	8 <i>c</i>	0.2448(1)	<i>x</i>	<i>x</i>	0.027(1)	<i>U</i> ₁₁	<i>U</i> ₁₁	−0.0089(5)	<i>U</i> ₁₂	<i>U</i> ₁₂
Br(2)	24 <i>d</i>	0.0244(3)	0.0123(2)	0.2450(1)	0.024(1)	0.021(1)	0.022(1)	−0.0040(9)	0.0071(6)	0.0103(5)
Si(1)	8 <i>c</i>	0.1313(2)	<i>x</i>	<i>x</i>	0.010(2)	<i>U</i> ₁₁	<i>U</i> ₁₁	0.001(1)	<i>U</i> ₁₂	<i>U</i> ₁₂

* Correspondence author (e-mail: J.Koehler@fkf.mpg.de)

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